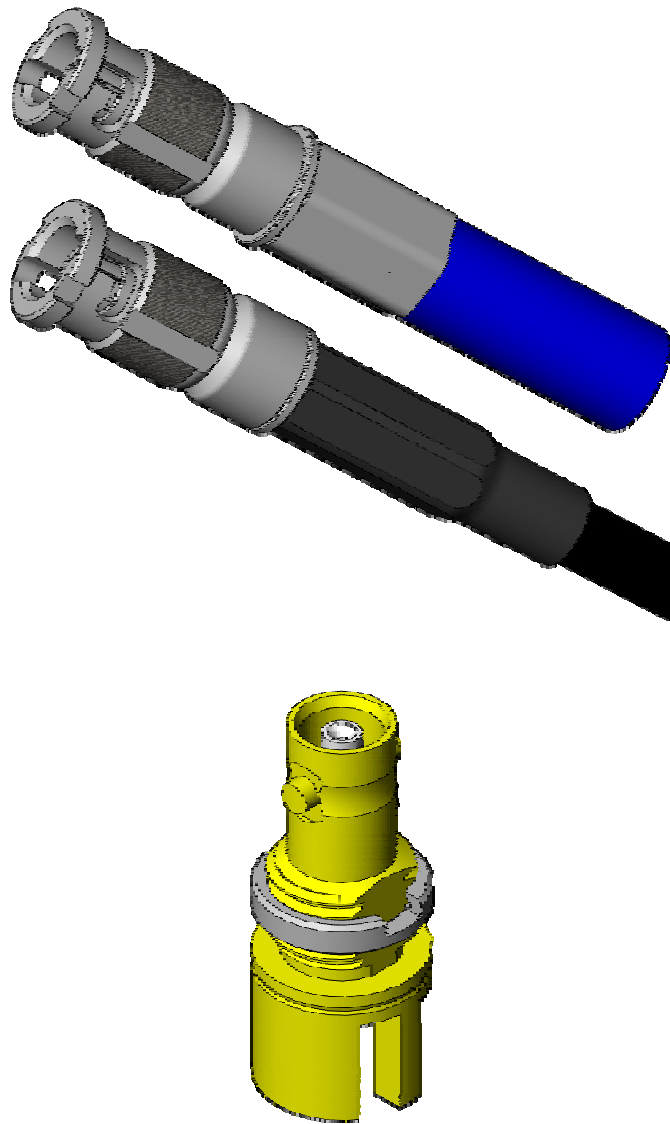




Project Number: Design Qualification Test Report		Tracking Code: 166103_Report_Rev_1	
Requested by: Chris Shelly		Date: 6/22/2012	Product Rev: N/A
Part #: RFB6T-H4SP2-606060-0150 \ HDBNC-J-P-HN-ST-EM1		Lot #: N/A	Tech: Craig Ryan Eng: Eric Mings
Part description: RFB6T \ HDBNC			Qty to test: 80
Test Start: 10/20/2011	Test Completed: 11/29/2011		



DESIGN QUALIFICATION TEST REPORT

**RFB6T \ HDBNC
RFB6T-H4SP2-606060-0150 \ HDBNC-J-P-HN-ST-EM1**

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

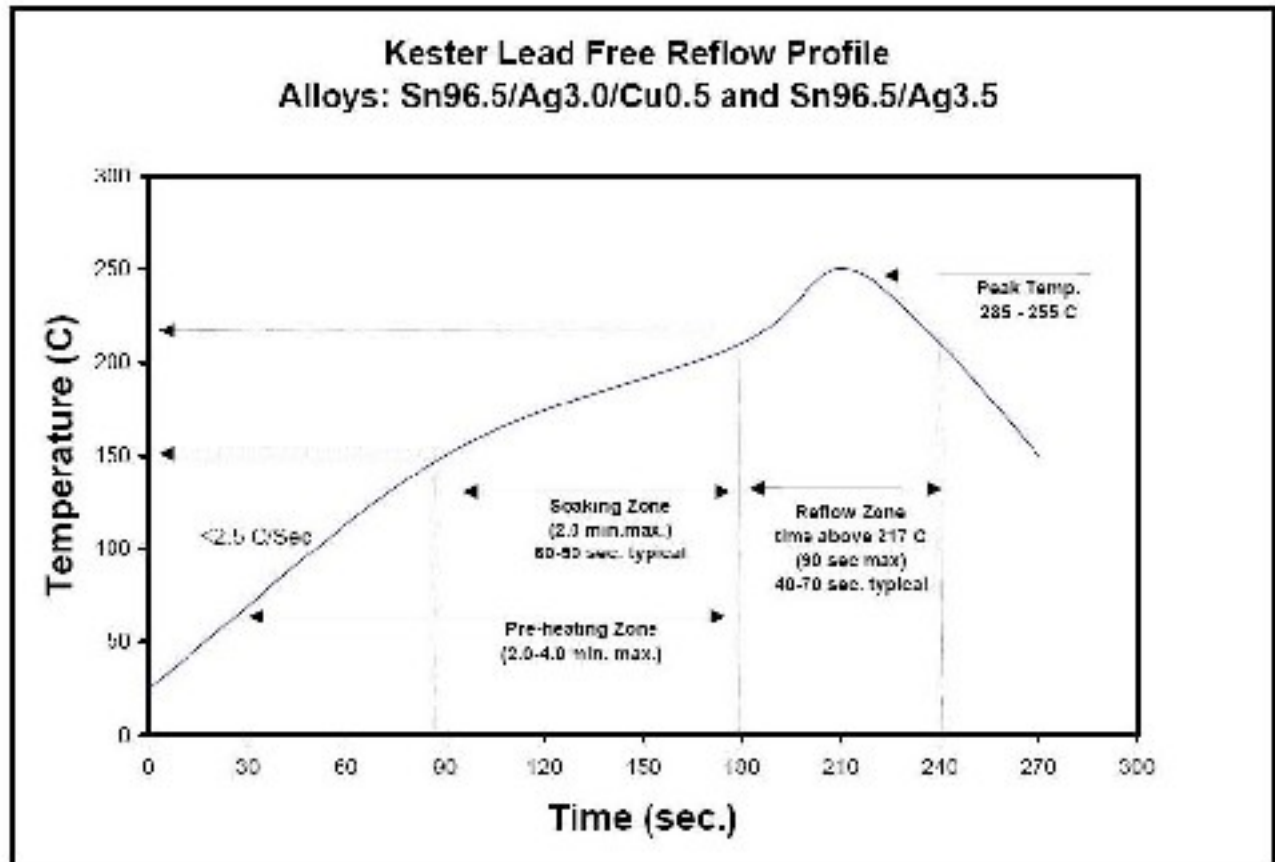
To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-103328-TST

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS**Gas Tight**

TEST	GROUP A1 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND
STEP	
01	LLCR-1
02	Gas Tight
03	LLCR-2

Gas Tight = EIA-364-36A

LLCR = EIA-364-23, LLCR

use Keithley 580 in the dry circuit mode, 10 mA Max

Normal Force

TEST	GROUP B1	GROUP B2	GROUP B3	GROUP B4
STEP	(10 MIN) HDBNC-J-P-H-ST-EM1-SKT	(10 MIN) HDBNC-J-P-H-ST-EM1-SKT HDBNC-P-C-H-ST-CA6-PIN	(10 MIN) HDBNC-P-C-N-ST-SHL	(10 MIN) HDBNC-P-C-N-ST-SHL HDBNC-J-P-N-ST-EM1-SHL
1	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps
02	Setup Approved	Thermal Aging (Mated and Undisturbed)	Setup Approved	Thermal Aging (Mated and Undisturbed)
03	Normal Force	Contact Gaps	Normal Force	Contact Gaps
04		Setup Approved		Setup Approved
05		Normal Force		Normal Force

Thermal Aging = EIA-364-17, Test Condition 4 (105°C)

Time Condition 'B' (250 Hours)

Normal Force = EIA-364-04

(Perpendicular) Displacement Force = 12.7 mm/min ± 6 mm/min

Spec is 50 N @ 1 mm displacement

Contact Gaps / Height - No standard method. Usually measured optically

Gaps to be taken on a minimum of 20% of each part tested

FLOWCHARTS Continued**Thermal Aging**

TEST	GROUP C1 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND
STEP	
1	Contact Gaps
2	LLCR-1
3	Thermal Aging (Mated and Undisturbed)
4	LLCR-2
5	Contact Gaps

Thermal Aging = EIA-364-17, Test Condition 4 (105°C)

Time Condition 'B' (250 Hours)

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

Durability/Gaps

TEST	GROUP D1 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND	GROUP D2 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND	GROUP D3 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND	GROUP D4 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND	GROUP D5 (8 MIN) HDBNC-J-P-HN-ST-EM1 RFB6T-H4SP2-606060-0150 SIGNAL & GROUND
STEP					
01	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps
02	LLCR-1	LLCR-1	LLCR-1	LLCR-1	LLCR-1
03	100 Cycles	200 Cycles	300 Cycles	400 Cycles	500 Cycles
04	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps	Contact Gaps
05	LLCR-2	LLCR-2	LLCR-2	LLCR-2	LLCR-2
06	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)	Thermal Shock (Mated and Undisturbed)
07	LLCR-3	LLCR-3	LLCR-3	LLCR-3	LLCR-3
08	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)	Cyclic Humidity (Mated and Undisturbed)
09	LLCR-4	LLCR-4	LLCR-4	LLCR-4	LLCR-4

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

FLOWCHARTS Continued**IR & DWV**

TEST STEP	GROUP E1 (2 MIN) RFB6T-H4SP2-606060-0150 HDBNC-J-P-HN-ST-EM1 Break Down - Pin to Ground	GROUP E2 (2 MIN) RF68T-H4SP2-606060-0150 Break Down - Pin to Ground	GROUP E3 (2 MIN) HDBNC-J-P-HN-ST-EM1 Break Down - Pin to Ground	GROUP F1 (2 MIN) RFB6T-H4SP2-606060-0150 HDBNC-J-P-HN-ST-EM1 IR/DWV - Pin to Ground
01	DWV/Break Down Voltage	DWV/Break Down Voltage	DWV/Break Down Voltage	IR & DWV at test voltage (on both mated sets and on each connector unmated)
02				Thermal Shock (both sets unmated)
03				IR & DWV at test voltage (on both mated sets and on each connector unmated)
04				Cyclic Humidity (both sets unmated)
05				IR & DWV at test voltage (on both mated sets and on each connector unmated)

DWV on group B1 to be performed at Test Voltage

DWV test voltage PER BS EN 122340:2002 Minimum or equal to 75% of the lowest break down voltage from group A1, A2 or A3

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

IR = EIA-364-21

DWV = EIA-364-20, Test Condition 1

Mechanical Shock / Vibration / LLCR

TEST STEP	GROUP G1 (8 MIN) RFB6T-H4SP2-606060-0150 HDBNC-J-P-HN-ST-EM1 SIGNAL & GROUND
01	LLCR-1
02	Shock
03	Vibration
04	LLCR-2

Mechanical Shock = EIA 364-27 Half Sine,

100 g's, 6 milliSeconds (Condition "C") each axis

Vibration = EIA 364-28, Random Vibration

7.56 g RMS, Condition VB — 2 hours/axis

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

FLOWCHARTS Continued**Shock / Vibration / nanoSecond Event Detection**

TEST	GROUP H1
STEP	(8 MIN) RFB6T-H4SP2-606060-0150 HDBNC-J-P-HN-ST-EM1 SIGNAL & GROUND
01	Event Detection, Shock
02	Event Detection, Vibration

Mechanical Shock = EIA 364-27 Half Sine,
100 g's, 6 milliSeconds (Condition "C") each axis

Vibration = EIA 364-28, Random Vibration

7.56 g RMS, Condition VB -- 2 hours/axis

Event detection requirement during Shock / Vibration is 50 nanoseconds minimum

Connector Pull

TEST STEP	GROUP 3 a 5 Pieces HDBNC-P-C-H-ST-CA6 -PIN soldered to CCA-1694A	GROUP 3 b 5 Pieces HDBNC-P-C-H-ST-CA8 -PIN soldered to CCA-1855A	GROUP 3 c 5 Pieces RFB6T-H4SP2-606060-0150 SIG & GND 0° Connector to Cable
01	Center contact only to cable 0° Pull test, Continuity	Center contact only to cable 0° Pull test, Continuity	Pull test, Continuity

Monitor continuity on both center and outer contactes and pull; record forces when continuity fails on both the center and outer contacts.

FLOWCHARTS Continued**Durability/Gaps**

TEST STEP	GROUP D6 (8 MIN) HDBNC-J-P-GN-ST-EM1 RFB6T-H4SP3-606060-0150 SIGNAL & GROUND
01	Contact Gaps
02	LLCR-1
03	100 Cycles
04	Contact Gaps
05	LLCR-2
06	Thermal Shock (Mated and Undisturbed)
07	LLCR-3
08	Cyclic Humidity (Mated and Undisturbed)
09	LLCR-4

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition B (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

Mating / Unmating Forces = EIA-364-13

Contact Gaps / Height - No standard method. Usually measured optically.

Gaps to be taken on a minimum of 20% of each part tested

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

THERMAL:

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition 4 at 105° C.
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

CONTACT GAPS:

- 1) Gaps above the surrounding plastic surface were measured before and after stressing the contacts (e.g. thermal aging, mechanical cycling, etc.).
- 2) Typically, all contacts on the connector are measured.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G² / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure
- 4) Procedure:
 - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
 - b. Test Conditions:
 - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
 - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
 - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
 - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
 - v. Exposure time, 55 to 65 minutes.
 - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
 - vii. The samples shall be dried after exposure for a minimum of 1 hour.
 - viii. Drying temperature 50° C
 - ix. The final LLCR shall be conducted within 1 hour after drying.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the loose state, *not* inserted in connector housing.
- 3) The contacts shall be prepared to allow access to the spring member at the same attitude and deflection level as would occur in actual use.
- 4) In the event that portions of the contact prevent insertion of the test probe and/or deflection of the spring member under evaluation, said material shall be removed leaving the appropriate contact surfaces exposed.
- 5) In the case of multi-tine contacts, each tine shall be tested independently on separate samples as required.
- 6) The connector housing shall be simulated, if required, in order to provide an accurate representation of the actual contact system performance.
- 7) A holding fixture shall be fashioned to allow the contact to be properly deflected.
- 8) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC², computer controlled test stand with a deflection measurement system accuracy of 5 μm (0.0002”).
- 9) The probe shall be attached to a Dillon P/N 49761-0105, 5 N (1.1 Lb) load cell providing an accuracy of $\pm 0.2\%$.
- 10) The nominal deflection rate shall be 5 mm (0.2”)/minute.
- 11) Unless otherwise noted a minimum of five contacts shall be tested.
- 12) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 13) The system shall utilize the TC² software in order to acquire and record the test data.
- 14) The permanent set of each contact shall be measured within the TC² software.
- 15) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

1) PROCEDURE:

- a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
- b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs

2) MEASUREMENTS/CALCULATIONS

- a. The breakdown voltage shall be measured and recorded.
- b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
- c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

CONNECTOR PULL:

- 1) Secure cable near center and pull on connector
 - a. At 0°, in-line with cable



Fig. 1

(Typical set-up, actual part not depicted.)

0° Connector pull, notice the electrical continuity hook-up wires.

RESULTS

Contact Gaps:

Normal Force Group

HDBNC-J-P-H-ST-EM1-SKT

Normal Force Initial T1

- Initial
 - Min----- 0.2792 mm
 - Max----- 0.3032 mm

Normal Force Thermal T1

- Initial
 - Min----- 0.2800 mm
 - Max----- 0.3020 mm
- After Thermal
 - Min----- 0.2781 mm
 - Max----- 0.3072 mm

HDBNC-P-C-N-ST-SHL

Normal Force Initial T1

- Initial
 - Min----- 3.6740 mm
 - Max----- 3.7990 mm

Normal Force Thermal T1

- Initial
 - Min----- 3.6480 mm
 - Max----- 3.7620 mm
- After Thermal
 - Min----- 3.6212 mm
 - Max----- 3.6943 mm

Thermal Aging Group

Signal Pin

- Initial
 - Min----- 0.2810 mm
 - Max----- 0.3030 mm
- After Thermal
 - Min----- 0.2664 mm
 - Max----- 0.3032 mm

Ground Pin

- Initial
 - Min----- 3.4290 mm
 - Max----- 3.7490 mm
- After Thermal
 - Min----- 3.4582 mm
 - Max----- 3.7111 mm

RESULTS Continued**Contact Gaps:****Durability/Gaps Group****HDBNC-J-P-GN-ST-EM1/RFB6T-H4SP3-606060-0150**

- **Initial**
 - **Min----- 0.2959 mm**
 - **Max----- 0.3150 mm**
- **After 100 cycles**
 - **Min----- 0.3069 mm**
 - **Max----- 0.3162 mm**

Durability/Gaps Group**100 cycles****Signal Pin**

- **Initial**
 - **Min----- 0.2850 mm**
 - **Max----- 0.3111 mm**
- **After 100 cycles**
 - **Min----- 0.2834 mm**
 - **Max----- 0.3132 mm**

Ground Pin

- **Initial**
 - **Min----- 3.3960 mm**
 - **Max----- 3.7265 mm**
- **After 100 cycles**
 - **Min----- 3.4315 mm**
 - **Max----- 3.6977 mm**

200 cycles**Signal Pin**

- **Initial**
 - **Min----- 0.2841 mm**
 - **Max----- 0.2981 mm**
- **After 200 cycles**
 - **Min----- 0.2893 mm**
 - **Max----- 0.3130 mm**

Ground Pin

- **Initial**
 - **Min----- 3.5864 mm**
 - **Max----- 3.7015 mm**
- **After 200 cycles**
 - **Min----- 3.6025 mm**
 - **Max----- 3.6577 mm**

RESULTS Continued**Contact Gaps:****Durability/Gaps Group****300 cycles****Signal Pin**

- **Initial**
 - **Min**----- **0.2811 mm**
 - **Max**----- **0.2971 mm**
- **After 300 cycles**
 - **Min**----- **0.2723 mm**
 - **Max**----- **0.3073 mm**

Ground Pin

- **Initial**
 - **Min**----- **3.5756 mm**
 - **Max**----- **3.6978 mm**
- **After 300 cycles**
 - **Min**----- **3.5732 mm**
 - **Max**----- **3.6972 mm**

400 cycles**Signal Pin**

- **Initial**
 - **Min**----- **0.2821 mm**
 - **Max**----- **0.3020 mm**
- **After 400 cycles**
 - **Min**----- **0.2822 mm**
 - **Max**----- **0.3174 mm**

Ground Pin

- **Initial**
 - **Min**----- **3.5462 mm**
 - **Max**----- **3.6907 mm**
- **After 400 cycles**
 - **Min**----- **3.5139 mm**
 - **Max**----- **3.6785 mm**

500 cycles**Signal Pin**

- **Initial**
 - **Min**----- **0.2841 mm**
 - **Max**----- **0.2991 mm**
- **After 500 cycles**
 - **Min**----- **0.2872 mm**
 - **Max**----- **0.3098 mm**

Ground Pin

- **Initial**
 - **Min**----- **3.5645 mm**
 - **Max**----- **3.7495 mm**
- **After 500 cycles**
 - **Min**----- **3.5550 mm**
 - **Max**----- **3.6597 mm**

RESULTS Continued**Normal Force at 0.0015 in deflection****HDBNC-J-P-H-ST-EM1-SKT**

- **Initial**
 - **Min**-----64.60 gf **Set** -----0.0000 in
 - **Max**-----116.80 gf **Set** -----0.0000 in
- **Thermal**
 - **Min**-----89.40 gf **Set** -----0.0000 in
 - **Max**-----128.40 gf **Set** -----0.0001 in

Normal Force at 0.0041 in deflection**HDBNC-P-C-N-ST-SHL**

- **Initial**
 - **Min**-----177.50 gf **Set** -----0.0000 in
 - **Max**-----216.50 gf **Set** -----0.0001 in
- **Thermal**
 - **Min**-----173.90 gf **Set** -----0.0004 in
 - **Max**-----235.10 gf **Set** -----0.0010 in

Connector Pull**HDBNC-P-C-H-ST-CA6-PIN**

- **Min**-----38.50 Lbs
- **Max**-----40.50 Lbs

HDBNC-P-C-H-ST-CA8-PIN

- **Min**-----17.50 Lbs
- **Max**-----18.00 Lbs

RFB6T-H4SP2-606060-0150

- **Min**-----34.50 Lbs
- **Max**-----41.50 Lbs

RESULTS Continued**Insulation Resistance minimums, IR**

- **Initial**
 - **Mated ----- 10000Meg Ω ----- Passed**
 - **Unmated ----- 50000Meg Ω ----- Passed**
- **Thermal**
 - **Mated ----- 10000Meg Ω ----- Passed**
 - **Unmated ----- 10000Meg Ω ----- Passed**
- **Humidity**
 - **Mated ----- 10000Meg Ω ----- Passed**
 - **Unmated ----- 10000Meg Ω ----- Passed**

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
 - **Breakdown Voltage ----- 1000 VAC**
 - **Test Voltage ----- 750 VAC**
 - **Working Voltage ----- 250 VAC**
- **Initial DWV ----- Passed**
- **Thermal DWV ----- Passed**
- **Humidity DWV ----- Passed**

RESULTS Continued**LLCR Gas Tight (16 LLCR test points)**

- **Initial**----- 11.33mOhms Max
- **Gas-Tight**
 - <= +5.0 mOhms ----- 16 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

LLCR Thermal Aging (16 LLCR test points)

- **Initial**----- 11.93mOhms Max
- **Thermal**
 - <= +5.0 mOhms ----- 15 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 1 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

LLCR Mechanical Shock & Random Vibration (16 LLCR test points)

- **Initial**----- 16.29mOhms Max
- **Shock & Vibration**
 - <= +5.0 mOhms ----- 14 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

Mechanical Shock & Random Vibration:

- **Shock**
 - **No Damage** ----- Passed
 - **50 Nanoseconds** ----- Passed
- **Vibration**
 - **No Damage** ----- Passed
 - **50 Nanoseconds** ----- Passed

RESULTS Continued**LLCR Durability:****100 cycles (16 LLCR test points)**

- **Initial** ----- 12.77mOhms Max
- **Durability, 100 Cycles**
 - <= +5.0 mOhms ----- 14 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 11 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 3 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 2 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 14 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

200 cycles (16 LLCR test points)

- **Initial** ----- 11.46mOhms Max
- **Durability, 200 Cycles**
 - <= +5.0 mOhms ----- 9 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 4 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 2 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 13 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 1 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 2 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 9 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 5 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 1 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued**LLCR Durability:****300 cycles (16 LLCR test points)**

- **Initial** ----- 11.37mOhms Max
- **Durability, 300 Cycles**
 - <= +5.0 mOhms ----- 11 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 2 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 13 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 3 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 10 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 4 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 1 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

400 cycles (16 LLCR test points)

- **Initial** ----- 12.94mOhms Max
- **Durability, 400 Cycles**
 - <= +5.0 mOhms ----- 10 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 3 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 3 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 12 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 4 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 11 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 4 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 1 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued**LLCR Durability:****500 cycles (16 LLCR test points)**

- **Initial**----- 11.88mOhms Max
- **Durability, 500 Cycles**
 - <= +5.0 mOhms ----- 12Points-----Stable
 - +5.1 to +10.0 mOhms ----- 2 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 2 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 16 Points-----Stable
 - +5.1 to +10.0 mOhms ----- 0 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 0 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 14 Points-----Stable
 - +5.1 to +10.0 mOhms ----- 2 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 0 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure

LLCR Durability:**HDBNC-J-P-GN-ST-EM1/RFB6T-H4SP3-606060-0150****100 cycles (16 LLCR test points)**

- **Initial**----- 13.59mOhms Max
- **Durability, 500 Cycles**
 - <= +5.0 mOhms ----- 15 Points-----Stable
 - +5.1 to +10.0 mOhms ----- 1 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 0 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 11 Points-----Stable
 - +5.1 to +10.0 mOhms ----- 3 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 2 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 11 Points-----Stable
 - +5.1 to +10.0 mOhms ----- 3 Points-----Minor
 - +10.1 to +15.0 mOhms ----- 2 Points-----Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points-----Marginal
 - +50.1 to +2000 mOhms ----- 0 Points-----Unstable
 - >+2000 mOhms ----- 0 Points-----Open Failure

DATA SUMMARIES**Contact Gaps:****Normal Force Group (HDBNC-J-P-H-ST-EM1-SKT)****Normal Force Initial T1**

Pin Type 1	
Signal	
<i>Nominal</i>	0.31
<i>Hi Limit</i>	0.33
<i>Lo Limit</i>	0.28
<i>Min</i>	0.2792
<i>Max</i>	0.3032
<i>Avg</i>	0.2885
<i>St. Dev.</i>	0.0069
<i>Count</i>	10

Normal Force Thermal T1

Initial	
Pin Type 1	
Signal	
<i>Nominal</i>	0.31
<i>Hi Limit</i>	0.33
<i>Lo Limit</i>	0.28
<i>Min</i>	0.2800
<i>Max</i>	0.3020
<i>Avg</i>	0.2880
<i>St. Dev.</i>	0.0070
<i>Count</i>	10

After Thermal

Pin Type 1	
Signal	
<i>Nominal</i>	0.31
<i>Hi Limit</i>	0.33
<i>Lo Limit</i>	0.28
<i>Min</i>	0.2781
<i>Max</i>	0.3072
<i>Avg</i>	0.2919
<i>St. Dev.</i>	0.0086
<i>Count</i>	10

DATA SUMMARIES Continued**Contact Gaps:****Normal Force Group (HDBNC-P-C-N-ST-SHL)****Normal Force Initial T1**

Pin Type 2	
Ground	
<i>Nominal</i>	3.73
<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	3.7
<i>Min</i>	3.6740
<i>Max</i>	3.7990
<i>Avg</i>	3.7150
<i>St. Dev.</i>	0.0430
<i>Count</i>	10

Normal Force Thermal T1

Initial	
Pin Type 2	
Ground	
<i>Nominal</i>	3.73
<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	3.7
<i>Min</i>	3.6480
<i>Max</i>	3.7260
<i>Avg</i>	3.6990
<i>St. Dev.</i>	0.0260
<i>Count</i>	10

After Thermal

Pin Type 2	
Ground	
<i>Nominal</i>	3.73
<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	3.7
<i>Min</i>	3.6212
<i>Max</i>	3.6943
<i>Avg</i>	3.6648
<i>St. Dev.</i>	0.0220
<i>Count</i>	10

DATA SUMMARIES Continued**Contact Gaps:****Thermal Aging Group (HDBNC-J-P-HN-ST-EM1/RFB6T-H4SP2-606060-0150)****Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.7
<i>Min</i>	0.2810	<i>Min</i>	3.4290
<i>Max</i>	0.3030	<i>Max</i>	3.7490
<i>Avg</i>	0.2940	<i>Avg</i>	3.6430
<i>St. Dev.</i>	0.0080	<i>St. Dev.</i>	0.0930
<i>Count</i>	8	<i>Count</i>	8

After Thermal

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.7
<i>Min</i>	0.2664	<i>Min</i>	3.4582
<i>Max</i>	0.3032	<i>Max</i>	3.7111
<i>Avg</i>	0.2945	<i>Avg</i>	3.6401
<i>St. Dev.</i>	0.0116	<i>St. Dev.</i>	0.0745
<i>Count</i>	8	<i>Count</i>	8

Durability/Gaps Group (HDBNC-J-P-GN-ST-EM1/RFB6T-H4SP3-606060-0150)**Initial**

<i>Pin Type 1</i>	
<i>Nominal</i>	0.31
<i>Hi Limit</i>	0.3300
<i>Lo Limit</i>	0.2800
<i>Min</i>	0.2959
<i>Max</i>	0.3150
<i>Avg</i>	0.3021
<i>St. Dev.</i>	0.0059
<i>Count</i>	8

After Thermal

<i>Pin Type 1</i>	
<i>Nominal</i>	0.31
<i>Hi Limit</i>	0.33
<i>Lo Limit</i>	0.28
<i>Min</i>	0.3069
<i>Max</i>	0.3162
<i>Avg</i>	0.3120
<i>St. Dev.</i>	0.0034
<i>Count</i>	8

DATA SUMMARIES Continued**Contact Gaps:****Durability/Gaps Group (100 Cycles)****Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2850	<i>Min</i>	3.3960
<i>Max</i>	0.3111	<i>Max</i>	3.7265
<i>Avg</i>	0.2916	<i>Avg</i>	3.6121
<i>St. Dev.</i>	0.0085	<i>St. Dev.</i>	0.0974
<i>Count</i>	8	<i>Count</i>	8

After 100 cycles

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2834	<i>Min</i>	3.4135
<i>Max</i>	0.3132	<i>Max</i>	3.6977
<i>Avg</i>	0.2950	<i>Avg</i>	3.6291
<i>St. Dev.</i>	0.0094	<i>St. Dev.</i>	0.0939
<i>Count</i>	8	<i>Count</i>	8

Durability/Gaps Group (200 Cycles)**Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2841	<i>Min</i>	3.5864
<i>Max</i>	0.2981	<i>Max</i>	3.7015
<i>Avg</i>	0.2903	<i>Avg</i>	3.6474
<i>St. Dev.</i>	0.0051	<i>St. Dev.</i>	0.0423
<i>Count</i>	8	<i>Count</i>	8

After 200 Cycles

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2893	<i>Min</i>	3.6025
<i>Max</i>	0.3130	<i>Max</i>	3.6577
<i>Avg</i>	0.3002	<i>Avg</i>	3.6364
<i>St. Dev.</i>	0.0080	<i>St. Dev.</i>	0.0202
<i>Count</i>	8	<i>Count</i>	8

DATA SUMMARIES Continued**Contact Gaps:****Durability/Gaps Group (300 Cycles)****Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2811	<i>Min</i>	3.5756
<i>Max</i>	0.2971	<i>Max</i>	3.6978
<i>Avg</i>	0.2894	<i>Avg</i>	3.6453
<i>St. Dev.</i>	0.0061	<i>St. Dev.</i>	0.0451
<i>Count</i>	8	<i>Count</i>	8

After 300 Cycles

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2723	<i>Min</i>	3.5732
<i>Max</i>	0.3073	<i>Max</i>	3.6972
<i>Avg</i>	0.2970	<i>Avg</i>	3.6288
<i>St. Dev.</i>	0.0114	<i>St. Dev.</i>	0.0394
<i>Count</i>	8	<i>Count</i>	8

Durability/Gaps Group (400 Cycles)**Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2821	<i>Min</i>	3.5462
<i>Max</i>	0.3020	<i>Max</i>	3.6907
<i>Avg</i>	0.2911	<i>Avg</i>	3.6288
<i>St. Dev.</i>	0.0074	<i>St. Dev.</i>	0.0548
<i>Count</i>	8	<i>Count</i>	8

After 400 Cycles

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2822	<i>Min</i>	3.5139
<i>Max</i>	0.3174	<i>Max</i>	3.6785
<i>Avg</i>	0.3003	<i>Avg</i>	3.6163
<i>St. Dev.</i>	0.0106	<i>St. Dev.</i>	0.0592
<i>Count</i>	8	<i>Count</i>	8

DATA SUMMARIES Continued**Contact Gaps:****Durability/Gaps Group (500 Cycles)****Initial**

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2841	<i>Min</i>	3.5645
<i>Max</i>	0.2991	<i>Max</i>	3.7495
<i>Avg</i>	0.2911	<i>Avg</i>	3.6392
<i>St. Dev.</i>	0.0055	<i>St. Dev.</i>	0.0539
<i>Count</i>	8	<i>Count</i>	8

After 500 Cycles

<i>Pin Type 1</i>		<i>Pin Type 2</i>	
Signal		Ground	
<i>Nominal</i>	0.31	<i>Nominal</i>	3.73
<i>Hi Limit</i>	0.33	<i>Hi Limit</i>	3.76
<i>Lo Limit</i>	0.28	<i>Lo Limit</i>	3.70
<i>Min</i>	0.2872	<i>Min</i>	3.5550
<i>Max</i>	0.3098	<i>Max</i>	3.6597
<i>Avg</i>	0.2975	<i>Avg</i>	3.6178
<i>St. Dev.</i>	0.0080	<i>St. Dev.</i>	0.0326
<i>Count</i>	8	<i>Count</i>	8

DATA SUMMARIES Continued**NORMAL FORCE (FOR CONTACTS TESTED OUTSIDE THE HOUSING):**

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) Typically, 8-10 readings are taken and the averages reported.

HDBNC-J-P-H-ST-EM1-SKT

Initial	Deflections in inches Forces in Grams										
	<u>0.0002</u>	<u>0.0003</u>	<u>0.0005</u>	<u>0.0006</u>	<u>0.0008</u>	<u>0.0009</u>	<u>0.0011</u>	<u>0.0012</u>	<u>0.0014</u>	<u>0.0015</u>	<i>SET</i>
Averages	8.77	15.57	21.65	30.17	39.42	49.98	60.71	72.26	83.79	95.48	0.0000
Min	5.60	11.30	15.50	22.00	26.80	33.20	38.60	46.20	55.80	64.60	0.0000
Max	11.70	20.80	27.70	39.20	53.30	66.60	76.90	93.00	104.00	116.80	0.0000
St. Dev	2.130	3.237	4.017	5.029	6.960	9.024	10.326	12.461	13.193	14.514	0.0000
Count	10	10	10	10	10	10	10	10	10	10	10

After Thermals	Deflections in inches Forces in Grams										
	<u>0.0002</u>	<u>0.0003</u>	<u>0.0005</u>	<u>0.0006</u>	<u>0.0008</u>	<u>0.0009</u>	<u>0.0011</u>	<u>0.0012</u>	<u>0.0014</u>	<u>0.0015</u>	<i>SET</i>
Averages	8.89	21.27	33.84	46.78	59.31	72.70	85.20	96.46	105.81	113.09	0.0000
Min	2.40	12.30	24.70	31.30	40.00	49.00	58.50	68.30	78.00	89.40	0.0000
Max	13.40	30.00	43.70	60.70	75.90	90.20	102.90	115.70	122.30	128.40	0.0001
St. Dev	3.832	5.616	6.580	9.305	11.021	12.625	14.554	14.967	14.398	12.142	0.0000
Count	10	10	10	10	10	10	10	10	10	10	10

HDBNC-P-C-N-ST-SHL

Initial	Deflections in inches Forces in Grams										
	<u>0.0004</u>	<u>0.0008</u>	<u>0.0012</u>	<u>0.0016</u>	<u>0.0021</u>	<u>0.0025</u>	<u>0.0029</u>	<u>0.0033</u>	<u>0.0037</u>	<u>0.0041</u>	<i>SET</i>
Averages	21.57	43.91	66.68	89.28	111.99	134.09	155.69	173.89	186.54	194.76	0.0000
Min	18.50	35.90	56.30	75.90	97.60	118.70	138.90	160.30	170.70	177.50	0.0000
Max	25.10	50.60	75.50	99.90	123.80	147.50	169.60	187.70	203.90	216.50	0.0001
St. Dev	2.020	4.578	6.095	7.652	8.498	9.486	10.204	8.462	10.979	11.731	0.0000
Count	10	10	10	10	10	10	10	10	10	10	10

After Thermals	Deflections in inches Forces in Grams										
	<u>0.0011</u>	<u>0.0011</u>	<u>0.0012</u>	<u>0.0016</u>	<u>0.0021</u>	<u>0.0025</u>	<u>0.0029</u>	<u>0.0033</u>	<u>0.0037</u>	<u>0.0041</u>	<i>SET</i>
Averages	28.43	28.43	36.23	61.16	86.05	111.13	136.16	161.34	182.70	196.11	0.0006
Min	3.60	3.60	11.10	39.20	67.80	94.20	123.30	144.60	164.60	173.90	0.0004
Max	42.90	42.90	52.30	80.00	108.00	137.40	164.80	193.50	220.80	235.10	0.0010
St. Dev	12.130	12.130	12.794	12.871	13.122	14.417	15.579	17.190	20.879	21.858	0.0002
Count	10	10	10	10	10	10	10	10	10	10	10

DATA SUMMARIES Continued**INSULATION RESISTANCE (IR):**

	Pin to Ground		
	Mated	Unmated	Unmated
Minimum	RFB6T/HDBNC	RFB6T	HDBNC
Initial	100000	50000	100000
Thermal	100000	100000	100000
Humidity	100000	100000	100000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	RFB6T/HDBNC
Break Down Voltage	1000
Test Voltage	750
Working Voltage	250

Pin to Ground	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued**LLCR Durability (100 cycles)**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms:----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
	2011-10-31	2011-11-29	2011-11-16	2011-11-29
Date	2011-10-31	2011-11-29	2011-11-16	2011-11-29
Room Temp (Deg C)	23	22	22	22
Rel Humidity (%)	32	30	36	30
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 100 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	11.05	0.45	0.59	0.45
St. Dev.	0.79	0.38	0.48	0.38
Min	10.24	0.02	0.12	0.11
Max	12.77	1.19	1.59	1.33
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	3.93	5.09	5.67	3.72
St. Dev.	0.91	2.17	3.73	1.80
Min	3.10	2.60	0.86	1.90
Max	5.94	9.59	10.92	7.13
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
100 Cycles	14	2	0	0	0	0
Therm Shck	11	3	2	0	0	0
Humidity	14	2	0	0	0	0

DATA SUMMARIES Continued**LLCR Durability (200 cycles)**

- 1). A total of 8 signal points and 8 ground points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2011-10-31	2011-11-11	2011-11-16	2011-11-29
Room Temp (Deg C)	23	22	22	22
Rel Humidity (%)	32	33	36	30
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 200 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	11.06	0.26	0.36	0.37
St. Dev.	0.32	0.12	0.34	0.25
Min	10.61	0.11	0.01	0.03
Max	11.46	0.40	1.02	0.78
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	3.74	12.22	5.21	7.21
St. Dev.	0.60	8.84	3.91	2.31
Min	3.15	3.26	2.08	3.09
Max	4.80	30.48	12.01	10.22
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
200 Cycles	9	4	1	2	0	0
Therm Shck	13	1	2	0	0	0
Humidity	9	5	1	1	0	0

DATA SUMMARIES Continued**LLCR Durability (300 cycles)**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2011-10-31	2011-11-11	2011-11-16	2011-11-29
Room Temp (Deg C)	23	22	22	22
Rel Humidity (%)	32	33	36	30
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 300 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	10.89	0.36	0.31	0.29
St. Dev.	0.43	0.22	0.17	0.22
Min	10.23	0.01	0.04	0.05
Max	11.37	0.73	0.62	0.70
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	4.82	8.52	4.10	8.87
St. Dev.	0.97	6.73	2.57	7.20
Min	3.15	0.89	1.28	2.11
Max	5.85	19.12	9.17	26.67
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
300 Cycles	11	2	1	2	0	0
Therm Shck	13	3	0	0	0	0
Humidity	10	4	1	1	0	0

DATA SUMMARIES Continued**LLCR Durability (400 cycles)**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2011-10-31	2011-11-11	2011-11-16	2011-11-29
Room Temp (Deg C)	23	22	22	30
Rel Humidity (%)	32	33	36	22
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 400 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	11.04	0.72	0.48	0.41
St. Dev.	0.84	0.86	0.56	0.52
Min	10.43	0.25	0.01	0.01
Max	12.94	2.80	1.74	1.67
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	4.50	8.08	4.23	5.78
St. Dev.	0.89	4.18	3.20	2.77
Min	3.39	1.67	0.39	2.47
Max	6.19	14.54	9.86	10.99
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
400 Cycles	10	3	3	0	0	0
Therm Shck	12	4	0	0	0	0
Humidity	11	4	1	0	0	0

DATA SUMMARIES Continued**LLCR Durability (500 cycles)**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2011-10-31	2011-11-11	2011-11-16	2011-11-29
Room Temp (Deg C)	23	22	22	22
Rel Humidity (%)	32	33	36	30
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 500 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	11.16	1.28	0.57	0.42
St. Dev.	0.47	2.53	0.53	0.42
Min	10.52	0.11	0.15	0.05
Max	11.88	7.54	1.70	1.33
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	4.27	5.82	1.76	3.46
St. Dev.	0.74	4.80	1.48	2.06
Min	3.39	0.29	0.07	0.55
Max	5.67	13.99	4.11	6.26
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
500 Cycles	12	2	2	0	0	0
Therm Shck	16	0	0	0	0	0
Humidity	14	2	0	0	0	0

DATA SUMMARIES Continued**LLCR Gas Tight:**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms: ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type		
	2011-10-20	2011-10-24
Date	2011-10-20	2011-10-24
Room Temp (Deg C)	22	22
Rel Humidity (%)	32	34
Technician	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta Acid Vapor
Pin Type 1: Signal		
Average	11.00	1.44
St. Dev.	0.24	0.07
Min	10.54	0.00
Max	11.33	0.20
Summary Count	8	8
Total Count	8	8
Pin Type 2: Ground		
Average	5.56	2.76
St. Dev.	1.47	1.43
Min	3.91	0.31
Max	8.92	4.37
Summary Count	8	8
Total Count	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
Acid Vapor	16	0	0	0	0	0

DATA SUMMARIES Continued**LLCR Thermal:**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type		
	2011-10-28	2011-11-11
Date	2011-10-28	2011-11-11
Room Temp (Deg C)	22	22
Rel Humidity (%)	33	33
Technician	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta Thermal
Pin Type 1: Signal		
Average	10.91	0.16
St. Dev.	0.40	0.10
Min	10.58	0.01
Max	11.93	0.33
Summary Count	8	8
Total Count	8	8
Pin Type 2: Ground		
Average	4.84	3.44
St. Dev.	1.83	1.82
Min	3.42	0.60
Max	9.41	6.05
Summary Count	8	8
Total Count	8	8

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
Thermal	15	1	0	0	0	0

DATA SUMMARIES Continued**LLCR Durability:(HDBNC-J-P-GN-ST-EM1/RFB6T-H4SP3-606060-0150)**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type				
Date	2012-1-18	2012-1-19	2012-1-25	2012-2-6
Room Temp (Deg C)	23	22	22	22
Rel Humidity (%)	36	35	36	35
Technician	Craig Ryan	Craig Ryan	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta 100 Cycles	Delta Therm Shck	Delta Humidity
Pin Type 1: Signal				
Average	11.35	0.56	0.94	1.19
St. Dev.	0.97	0.82	0.96	1.00
Min	10.39	0.00	0.17	0.19
Max	13.59	2.60	3.23	3.59
Summary Count	8	8	8	8
Total Count	8	8	8	8
Pin Type 2: Ground				
Average	5.65	2.65	6.09	6.52
St. Dev.	1.35	1.63	4.15	4.11
Min	3.48	0.58	0.88	1.30
Max	7.67	5.10	12.68	12.83
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
100 Cycles	15	1	0	0	0	0
Therm Shck	11	3	2	0	0	0
Humidity	11	3	2	0	0	0

DATA SUMMARIES Continued**LLCR Shock & Vibration:**

- 1) A total of 8 signal points and 8 ground points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type		
Date	2011-12-27	2011-12-30
Room Temp (Deg C)	22	23
Rel Humidity (%)	32	33
Technician	Craig Ryan	Craig Ryan
mOhm values	Actual Initial	Delta Shock-Vib
Pin Type 1: Ground		
Average	10.71	5.06
St. Dev.	1.32	1.47
Min	8.67	3.30
Max	13.24	7.56
Summary Count	8	8
Total Count	8	8
Pin Type 2: Signal		
Average	15.63	0.11
St. Dev.	0.32	0.06
Min	15.19	0.03
Max	16.29	0.23
Summary Count	8	8
Total Count	8	8

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	≤ 5	$>5 \ \& \ \leq 10$	$>10 \ \& \ \leq 15$	$>15 \ \& \ \leq 50$	$>50 \ \& \ \leq 1000$	>1000
Shock-Vib	12	4	0	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	16
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

DATA SUMMARIES Continued**Connector Pull****HDBNC-P-C-H-ST-CA6 -PIN**

	Force (lbs)
Minimum	38.50
Maximum	40.50
Average	39.50

HDBNC-P-C-H-ST-CA8-PIN

	Force (lbs)
Minimum	17.50
Maximum	18.00
Average	17.60

RFB6T-H4SP2-606060-0150

	Force (lbs)
Minimum	34.50
Maximum	41.50
Average	37.88

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** MO-04**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 0798688**Accuracy:** See Manual

... Last Cal: 04/30/2011, Next Cal: 04/30/2012

Equipment #: TCT-04**Description:** Dillon Quantrol TC2 Test Stand**Manufacturer:** Dillon Quantrol**Model:** TC2**Serial #:** 04-1041-04**Accuracy:** Speed Accuracy: +/- 5% of indicated speed; Displacement: +/- 5 micrometers.

... Last Cal: 05/21/2011, Next Cal: 05/21/2012

Equipment #: THC-02**Description:** Temperature/Humidity Chamber**Manufacturer:** Thermotron**Model:** SE-1000-6-6**Serial #:** 31808**Accuracy:** See Manual

... Last Cal: 02/16/2012, Next Cal: 02/16/2013

Equipment #: TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14993**Accuracy:** See Manual

... Last Cal: 05/18/2011, Next Cal: 05/18/2012

Equipment #: HPM-01**Description:** Hipot Megommeter**Manufacturer:** Hipotronics**Model:** H306B-A**Serial #:** M9905004**Accuracy:** 2 % Full Scale Accuracy

... Last Cal: 11/30/2011, Next Cal: 11/30/2012

EQUIPMENT AND CALIBRATION SCHEDULES Continued**Equipment #:** SVC-01**Description:** Shock & Vibration Table**Manufacturer:** Data Physics**Model:** LE-DSA-10-20K**Serial #:** 10037**Accuracy:** See Manual

... Last Cal: 11/31/2010, Next Cal: 11/31/2011

Equipment #: ACLM-01**Description:** Accelerometer**Manufacturer:** PCB Piezotronics**Model:** 352C03**Serial #:** 115819**Accuracy:** See Manual

... Last Cal: 07/09/2011, Next Cal: 07/09/2012

Equipment #: ED-03**Description:** Event Detector**Manufacturer:** Analysis Tech**Model:** 32EHD**Serial #:** 1100604**Accuracy:** See Manual

... Last Cal: 06/04/2011, Next Cal: 06/04/2012